Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/010,212	LEE ET AL.	
Examiner	Art Unit	
Matthew F. DeSanto	3763	

	SEARCHED					
Class	Subclass	Date	Examiner			
609	9661,264 573-576, 103.04	2/5/06	MF)			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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